

Notice of References Cited

Application/Control No.

10/573,685

Applicant(s)/Patent Under
Reexamination
NAKANISHI ET AL.

Examiner

Eric M. Blount

Art Unit

2612

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,218,758 B2	05-2007	Ishii et al.	340/988
*	B	US-2002/0044048 A1	04-2002	Watanabe et al.	340/436
*	C	US-6,636,258 B2	10-2003	Strumolo, Gary Steven	348/149
*	D	US-6,172,601 B1	01-2001	Wada et al.	340/436
*	E	US-7,126,460 B2	10-2006	Yamada, Keiichi	340/435
*	F	US-7,230,524 B2	06-2007	Watanabe et al.	340/435
*	G	US-6,583,403 B1	06-2003	Koike et al.	342/71
*	H	US-6,477,260 B1	11-2002	Shimomura, Noriko	340/435
*	I	US-5,757,290 A	05-1998	Watanabe et al.	340/988
*	J	US-7,307,655 B1	12-2007	Okamoto et al.	348/222.1
*	K	US-6,369,701 B1	04-2002	Yoshida et al.	340/435
*	L	US-2007/0057816 A1	03-2007	Sakakibara et al.	340/932.2
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.